Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/724,088	KOSHINO ET AL.
Examiner	Art Unit
Khai M. Nauven	2687

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	445 422.1 560 403 423	2/21/2006	KN
370	216 328 338	2/21/2006	KN
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEA		Y)
	DATE	EXMR
East (see attached)		Κ̈́N